Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | YUEH ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0176583	09-2003	Rhodes et al.	525/326.2
*	В	US-2003/0175620	09-2003	Toishi et al.	430/280.1
*	С	US-2004/0192867	09-2004	Narita et al.	526/242
*	D	US-6,359,153	03-2002	Lee et al.	549/463
*	E	US-5,336,815	08-1994	Becker et al.	568/857
*	F	US-2002/0042549	04-2002	Holdstock et al.	585/610
*	G	US-4,767,500	08-1988	Patt et al.	162/32
*	Н	US-2002/0016431	02-2002	Iwasa et al.	526/284
*	1	US-6,437,052	08-2002	Iwasa et al.	525/375
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1126322 A2	08-2001	European Patent	HARADA et al.	
	0					
	Р	·				
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.